

Notice of References Cited	Application/Control No. 10/607,165		Applicant(s)/Patent Under Reexamination HAAN ET AL	
	Examiner Anh t.n Vo		Art Unit 2861	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,220,702	04-2001	Nakamura et al.	347/86
*	B	US-2001/0040612	11-2001	SHIMIZU, SEIJI	347/86
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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